

S/N 09/834,751

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Sergey A. Velichko et al. Examiner: Craig S. Miller
Serial No.: 09/834,751 Group Art Unit: 2857
Filed: April 13, 2001 Docket: 303.750US1
Title: CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC
TESTING

COMMUNICATION CONCERNING RELATED APPLICATION(S)

MS Amendment

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Applicants would like to bring to the Examiner's attention the following related application(s) in the above-identified patent application:

<u>Serial/Patent No.</u>	<u>Filing Date/Issue Date</u>	<u>Attorney Docket</u>	<u>Title</u>
11/342419	January 30, 2006	303.821US3	DYNAMICALLY ADAPTABLE SEMICONDUCTOR PARAMETRIC TESTING
11/342425	January 30, 2006	303.821US4	DYNAMICALLY ADAPTABLE SEMICONDUCTOR PARAMETRIC TESTING
11/265897	November 3, 2005	303.855US2	DYNAMIC CREATION AND MODIFICATION OF WAFER TEST MAPS DURING WAFER TESTING

Continuations and divisionals may be later filed on the cases listed above, or cited to the Examiner in any previous Communication Concerning Related Applications. Applicants request

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that the Examiner review all continuations and divisionals of the above-listed or previously-cited patent applications before allowing the claims of the present patent application.

Respectfully submitted,

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CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being filed using the USPTO's electronic filing system EFS-Web,ans is addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 26 day of April, 2006.

KATE GANNON
Name


Signature